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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	25475
Number of Logic Elements/Cells	326080
Total RAM Bits	16404480
Number of I/O	500
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	900-BBGA, FCBGA
Supplier Device Package	900-FCBGA (31x31)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7k325t-1ffg900c

Table 1: Absolute Maximum Ratings ⁽¹⁾ (Cont'd)

Symbol	Description	Min	Max	Units
I_{DCIN}	DC input current for receiver input pins DC coupled $V_{MGTAVTT} = 1.2V$	–	14	mA
I_{DCOUT}	DC output current for transmitter pins DC coupled $V_{MGTAVTT} = 1.2V$	–	14	mA
XADC				
V_{CCADC}	XADC supply relative to GNDADC	–0.5	2.0	V
V_{REFP}	XADC reference input relative to GNDADC	–0.5	2.0	V
Temperature				
T_{STG}	Storage temperature (ambient)	–65	150	°C
T_{SOL}	Maximum soldering temperature for Pb/Sn component bodies ⁽⁶⁾	–	+220	°C
	Maximum soldering temperature for Pb-free component bodies ⁽⁶⁾	–	+260	°C
T_j	Maximum junction temperature ⁽⁶⁾	–	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- The lower absolute voltage specification always applies.
- For I/O operation, refer to [UG471: 7 Series FPGAs SelectIO Resources User Guide](#).
- The maximum limit applied to DC and AC signals.
- For maximum undershoot and overshoot AC specifications, see [Table 4](#) and [Table 5](#).
- For soldering guidelines and thermal considerations, see [UG475: 7 Series FPGA Packaging and Pinout Specification](#).

Table 2: Recommended Operating Conditions ⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
FPGA Logic					
$V_{CCINT}^{(2)}$	Internal supply voltage	0.97	1.00	1.03	V
	For -2L (0.9V) devices: internal supply voltage	0.87	0.90	0.93	V
$V_{CCBRAM}^{(2)}$	Block RAM supply voltage	0.97	1.00	1.03	V
	For -2L (0.9V) devices: block RAM supply voltage	0.87	0.90	1.03	V
V_{CCAUX}	Auxiliary supply voltage	1.71	1.80	1.89	V
$V_{CCO}^{(3)(4)}$	Supply voltage for 3.3V HR I/O banks	1.14	–	3.465	V
	Supply voltage for 1.8V HP I/O banks	1.14	–	1.89	V
V_{CCAUX_IO}	Auxiliary supply voltage when set to 1.8V	1.71	1.80	1.89	V
	Auxiliary supply voltage when set to 2.0V	1.94	2.00	2.06	V
$V_{IN}^{(5)}$	I/O input voltage	–0.20	–	$V_{CCO} + 0.2$	V
	I/O input voltage for V_{REF} and differential I/O standards	–0.20	–	2.625	V
$I_{IN}^{(6)}$	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	–	10	mA
$V_{CCBATT}^{(7)}$	Battery voltage	1.0	–	1.89	V
GTX Transceiver					
$V_{MGTAVCC}^{(8)}$	Analog supply voltage for the GTX transceiver QPLL frequency range ≤ 10.3125 GHz ⁽⁹⁾⁽¹⁰⁾	0.97	1.0	1.08	V
	Analog supply voltage for the GTX transceiver QPLL frequency range > 10.3125 GHz	1.02	1.05	1.08	V
$V_{MGTAVTT}^{(8)}$	Analog supply voltage for the GTX transmitter and receiver termination circuits	1.17	1.2	1.23	V
$V_{MGTVCCAUX}^{(8)}$	Auxiliary analog QPLL voltage supply for the transceivers	1.75	1.80	1.85	V

Table 5: Maximum Allowed AC Voltage Overshoot and Undershoot for 1.8V HP I/O Banks⁽¹⁾⁽²⁾ (Cont'd)

AC Voltage Overshoot	% of UI @–40°C to 100°C	AC Voltage Undershoot	% of UI @–40°C to 100°C
$V_{CCO} + 0.80$	9.71	–0.80	50.0
$V_{CCO} + 0.85$	4.51	–0.85	28.4
$V_{CCO} + 0.90$	2.12	–0.90	12.7
$V_{CCO} + 0.95$	1.01	–0.95	5.79

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20 μ s.

Table 6: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
I_{CCINTQ}	Quiescent V_{CCINT} supply current	XC7K70T	241	241	241	187	mA
		XC7K160T	474	474	474	368	mA
		XC7K325T	810	810	810	629	mA
		XC7K355T	993	993	993	771	mA
		XC7K410T	1080	1080	1080	838	mA
		XC7K420T	1313	1313	1313	1019	mA
		XC7K480T	1313	1313	1313	1019	mA
I_{CCOQ}	Quiescent V_{CCO} supply current	XC7K70T	1	1	1	1	mA
		XC7K160T	1	1	1	1	mA
		XC7K325T	1	1	1	1	mA
		XC7K355T	1	1	1	1	mA
		XC7K410T	1	1	1	1	mA
		XC7K420T	1	1	1	1	mA
		XC7K480T	1	1	1	1	mA
I_{CCAUXQ}	Quiescent V_{CCAUX} supply current	XC7K70T	21	21	21	21	mA
		XC7K160T	40	40	40	40	mA
		XC7K325T	68	68	68	68	mA
		XC7K355T	75	75	75	75	mA
		XC7K410T	85	85	85	85	mA
		XC7K420T	99	99	99	99	mA
		XC7K480T	99	99	99	99	mA
$I_{CCAUX_{IO}Q}$	Quiescent $V_{CCAUX_{IO}}$ supply current	XC7K70T	N/A	N/A	N/A	N/A	mA
		XC7K160T	2	2	2	2	mA
		XC7K325T	2	2	2	2	mA
		XC7K355T	N/A	N/A	N/A	N/A	mA
		XC7K410T	2	2	2	2	mA
		XC7K420T	N/A	N/A	N/A	N/A	mA
		XC7K480T	N/A	N/A	N/A	N/A	mA

Table 7 shows the minimum current, in addition to I_{CCQ} , that are required by Kintex-7 devices for proper power-on and configuration. If the current minimums shown in Table 6 and Table 7 are met, the device powers on after all five supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after V_{CCINT} is applied.

Once initialized and configured, use the XPower tools to estimate current drain on these supplies.

Table 7: Power-On Current for Kintex-7 Devices

Device	$I_{CCINTMIN}$ Typ ⁽¹⁾	$I_{CCAUXMIN}$ Typ ⁽¹⁾	I_{CCOMIN} Typ ⁽¹⁾	I_{CCAUX_IOMIN} Typ ⁽¹⁾	$I_{CCBRAMMIN}$ Typ ⁽¹⁾	Units
XC7K70T	$I_{CCINTQ} + 450$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 40$	mA
XC7K160T	$I_{CCINTQ} + 550$	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 40$	mA
XC7K325T	$I_{CCINTQ} + 600$	$I_{CCAUXQ} + 80$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 40$	mA
XC7K355T	$I_{CCINTQ} + 1450$	$I_{CCAUXQ} + 109$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 81$	mA
XC7K410T	$I_{CCINTQ} + 1500$	$I_{CCAUXQ} + 125$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 90$	mA
XC7K420T	$I_{CCINTQ} + 2200$	$I_{CCAUXQ} + 180$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 108$	mA
XC7K480T	$I_{CCINTQ} + 2200$	$I_{CCAUXQ} + 180$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 108$	mA

Notes:

- Typical values are specified at nominal voltage, 25°C.
- Use the XPower Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.

Table 8: Power Supply Ramp Time

Symbol	Description	Conditions	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 90% of V_{CCINT}		0.2	50	ms
T_{VCCO}	Ramp time from GND to 90% of V_{CCO}		0.2	50	ms
T_{VCCAUX}	Ramp time from GND to 90% of V_{CCAUX}		0.2	50	ms
T_{VCCAUX_IO}	Ramp time from GND to 90% of V_{CCAUX_IO}		0.2	50	ms
$T_{VCCBRAM}$	Ramp time from GND to 90% of V_{CCBRAM}		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625V$	$T_J = 100^{\circ}C^{(1)}$	–	500	ms
		$T_J = 85^{\circ}C^{(1)}$	–	800	
$T_{MGTAVCC}$	Ramp time from GND to 90% of $V_{MGTAVCC}$		0.2	50	ms
$T_{MGTAVTT}$	Ramp time from GND to 90% of $V_{MGTAVTT}$		0.2	50	ms
$T_{MGTVCCAUX}$	Ramp time from GND to 90% of $V_{MGTVCCAUX}$		0.2	50	ms

Notes:

- Based on 240,000 power cycles with nominal V_{CCO} of 3.3V or 36,500 power cycles with a worst case V_{CCO} of 3.465V.

Table 18: Maximum Physical Interface (PHY) Rate for Memory Interfaces (FBG Packages)⁽¹⁾⁽²⁾

Memory Standard	I/O Bank Type	V _{CCAUX_IO} ⁽³⁾	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
4:1 Memory Controllers							
DDR3	HP	N/A	1333	1066	800	800	Mb/s
	HR	N/A	1066	800	800	800	Mb/s
DDR3L	HP	N/A	1066	800	667	667	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	N/A	800	800	800	800	Mb/s
	HR	N/A	800	667	667	667	Mb/s
RLDRAM III ⁽⁴⁾	HP	N/A	550	500	450	450	MHz
	HR	N/A	N/A				
2:1 Memory Controllers							
DDR3	HP	N/A	1066	1066	800	800	Mb/s
	HR	N/A	1066	800	800	800	Mb/s
DDR3L	HP	N/A	1066	800	667	667	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	N/A	800	800	800	800	Mb/s
	HR	N/A	800	667	667	667	Mb/s
QDR II+ ⁽⁵⁾	HP	N/A	550	500	450	450	MHz
	HR	N/A	450	400	350	350	MHz
RLDRAM II	HP	N/A	533	500	450	450	MHz
	HR	N/A					
LPDDR2 ⁽⁴⁾	HP	N/A	667	667	667	667	Mb/s
	HR	N/A	667	667	533	533	Mb/s

Notes:

1. V_{REF} tracking is required. For more information, see [UG586](#), *7 Series FPGAs Memory Interface Solutions User Guide*.
2. When using the internal V_{REF} the maximum data rate is 800 Mb/s (400 MHz).
3. FBG packages do not have separate V_{CCAUX_IO} supply pins to adjust the pre-driver voltage of the HP I/O banks.
4. RLDRAM III (BL = 4, BL = 8) and LPDDR2 specifications have not been validated with memory IP.
5. The maximum QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations. Burst length 2 (BL = 2) implementations are limited to 333 MHz for all speed grades and I/O bank types.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T _{IOP1}				T _{IOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
HSTL_I_F	0.61	0.64	0.73	0.79	1.10	1.19	1.23	1.41	1.86	2.05	2.22	1.92	ns
HSTL_II_F	0.61	0.64	0.73	0.78	1.05	1.18	1.28	1.42	1.81	2.04	2.27	1.94	ns
HSTL_I_18_F	0.64	0.67	0.76	0.79	1.05	1.18	1.28	1.44	1.81	2.04	2.27	1.95	ns
HSTL_II_18_F	0.64	0.67	0.76	0.79	1.03	1.14	1.23	1.42	1.79	2.00	2.22	1.94	ns
DIFF_HSTL_I_F	0.63	0.67	0.77	0.78	1.09	1.18	1.22	1.48	1.85	2.04	2.21	2.00	ns
DIFF_HSTL_II_F	0.63	0.67	0.77	0.79	1.02	1.11	1.14	1.48	1.78	1.97	2.13	2.00	ns
DIFF_HSTL_I_18_F	0.65	0.69	0.78	0.79	1.08	1.17	1.21	1.48	1.84	2.03	2.20	2.00	ns
DIFF_HSTL_II_18_F	0.65	0.69	0.78	0.81	1.01	1.10	1.13	1.48	1.77	1.96	2.12	2.00	ns
LVC MOS33_S4	1.31	1.40	1.60	1.54	5.23	5.61	6.09	4.13	5.99	6.47	7.08	4.64	ns
LVC MOS33_S8	1.31	1.40	1.60	1.54	4.46	4.85	5.33	3.84	5.22	5.71	6.32	4.36	ns
LVC MOS33_S12	1.31	1.40	1.60	1.54	3.46	3.89	4.42	3.41	4.22	4.75	5.41	3.92	ns
LVC MOS33_S16	1.31	1.40	1.60	1.54	3.06	3.43	3.88	3.72	3.82	4.29	4.87	4.23	ns
LVC MOS33_F4	1.31	1.40	1.60	1.54	4.70	5.01	5.36	3.58	5.46	5.87	6.35	4.09	ns
LVC MOS33_F8	1.31	1.40	1.60	1.54	3.62	4.04	4.56	3.06	4.38	4.90	5.55	3.58	ns
LVC MOS33_F12	1.31	1.40	1.60	1.54	2.57	2.85	3.15	2.88	3.33	3.71	4.14	3.39	ns
LVC MOS33_F16	1.31	1.40	1.60	1.54	2.44	2.69	2.96	2.88	3.20	3.55	3.95	3.39	ns
LVC MOS25_S4	1.08	1.16	1.32	1.36	4.49	4.80	5.16	3.44	5.25	5.66	6.15	3.95	ns
LVC MOS25_S8	1.08	1.16	1.32	1.36	3.66	4.04	4.49	3.20	4.42	4.90	5.48	3.72	ns
LVC MOS25_S12	1.08	1.16	1.32	1.36	2.77	3.10	3.49	2.80	3.53	3.96	4.48	3.31	ns
LVC MOS25_S16	1.08	1.16	1.32	1.36	3.24	3.62	4.09	3.14	4.00	4.48	5.08	3.66	ns
LVC MOS25_F4	1.08	1.16	1.32	1.36	3.96	4.31	4.72	3.06	4.72	5.17	5.71	3.58	ns
LVC MOS25_F8	1.08	1.16	1.32	1.36	2.43	2.87	3.42	2.50	3.19	3.73	4.41	3.02	ns
LVC MOS25_F12	1.08	1.16	1.32	1.36	2.23	2.63	3.13	2.48	2.99	3.49	4.12	3.00	ns
LVC MOS25_F16	1.08	1.16	1.32	1.36	1.92	2.17	2.45	2.33	2.68	3.03	3.44	2.84	ns
LVC MOS18_S4	0.64	0.66	0.74	0.87	3.24	3.45	3.66	1.91	4.00	4.31	4.65	2.42	ns
LVC MOS18_S8	0.64	0.66	0.74	0.87	2.58	2.91	3.31	2.50	3.34	3.77	4.30	3.02	ns
LVC MOS18_S12	0.64	0.66	0.74	0.87	2.58	2.91	3.31	2.50	3.34	3.77	4.30	3.02	ns
LVC MOS18_S16	0.64	0.66	0.74	0.87	1.82	2.03	2.24	1.84	2.58	2.89	3.23	2.36	ns
LVC MOS18_S24 ⁽¹⁾	0.64	0.66	0.74	0.87	1.74	1.92	2.08	1.92	2.50	2.78	3.07	2.44	ns
LVC MOS18_F4	0.64	0.66	0.74	0.87	3.12	3.31	3.49	1.77	3.88	4.17	4.48	2.28	ns
LVC MOS18_F8	0.64	0.66	0.74	0.87	1.91	2.13	2.36	2.00	2.67	2.99	3.35	2.52	ns
LVC MOS18_F12	0.64	0.66	0.74	0.87	1.91	2.13	2.36	2.00	2.67	2.99	3.35	2.52	ns
LVC MOS18_F16	0.64	0.66	0.74	0.87	1.52	1.68	1.81	1.72	2.28	2.54	2.80	2.23	ns
LVC MOS18_F24 ⁽¹⁾	0.64	0.66	0.74	0.87	1.34	1.46	1.55	1.66	2.10	2.32	2.54	2.17	ns
LVC MOS15_S4	0.66	0.69	0.81	0.90	3.48	3.74	4.03	2.22	4.24	4.60	5.02	2.73	ns
LVC MOS15_S8	0.66	0.69	0.81	0.90	2.37	2.67	3.01	2.41	3.13	3.53	4.00	2.92	ns
LVC MOS15_S12	0.66	0.69	0.81	0.90	1.83	2.03	2.23	1.91	2.59	2.89	3.22	2.42	ns

Table 20: 1.8V IOB High Performance (HP) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
DIFF_HSTL_II_DCI_F	0.75	0.79	0.92	0.76	0.97	1.08	1.15	1.30	1.61	1.84	1.97	1.91	ns
DIFF_HSTL_I_18_F	0.75	0.79	0.92	0.89	1.04	1.16	1.24	1.38	1.68	1.91	2.06	1.99	ns
DIFF_HSTL_II_18_F	0.75	0.79	0.92	0.89	0.98	1.09	1.16	1.40	1.62	1.85	1.98	2.01	ns
DIFF_HSTL_I_DCI_18_F	0.75	0.79	0.92	0.75	1.04	1.16	1.24	1.38	1.67	1.91	2.06	1.99	ns
DIFF_HSTL_II_DCI_18_F	0.75	0.79	0.92	0.75	0.98	1.09	1.16	1.33	1.61	1.85	1.98	1.94	ns
DIFF_HSTL_II_T_DCI_18_F	0.75	0.79	0.92	0.76	1.04	1.16	1.24	1.38	1.67	1.91	2.06	1.99	ns
LVC MOS18_S2	0.47	0.50	0.60	0.87	3.95	4.28	4.85	3.40	4.59	5.04	5.67	4.01	ns
LVC MOS18_S4	0.47	0.50	0.60	0.87	2.67	2.98	3.43	2.69	3.31	3.73	4.26	3.30	ns
LVC MOS18_S6	0.47	0.50	0.60	0.87	2.14	2.38	2.72	2.18	2.77	3.14	3.54	2.79	ns
LVC MOS18_S8	0.47	0.50	0.60	0.87	1.98	2.21	2.52	2.02	2.61	2.97	3.35	2.63	ns
LVC MOS18_S12	0.47	0.50	0.60	0.87	1.70	1.91	2.17	1.85	2.34	2.67	2.99	2.46	ns
LVC MOS18_S16	0.47	0.50	0.60	0.87	1.57	1.75	1.97	1.76	2.20	2.51	2.79	2.37	ns
LVC MOS18_F2	0.47	0.50	0.60	0.87	3.50	3.87	4.48	2.85	4.14	4.63	5.30	3.46	ns
LVC MOS18_F4	0.47	0.50	0.60	0.87	2.23	2.50	2.87	2.26	2.87	3.25	3.69	2.87	ns
LVC MOS18_F6	0.47	0.50	0.60	0.87	1.80	2.00	2.26	1.52	2.43	2.76	3.08	2.13	ns
LVC MOS18_F8	0.47	0.50	0.60	0.87	1.46	1.72	2.04	1.51	2.10	2.47	2.86	2.12	ns
LVC MOS18_F12	0.47	0.50	0.60	0.87	1.26	1.40	1.53	1.46	1.89	2.16	2.35	2.07	ns
LVC MOS18_F16	0.47	0.50	0.60	0.87	1.19	1.33	1.44	1.46	1.83	2.08	2.26	2.07	ns
LVC MOS15_S2	0.59	0.62	0.73	0.86	3.55	3.89	4.45	3.11	4.19	4.65	5.27	3.73	ns
LVC MOS15_S4	0.59	0.62	0.73	0.86	2.45	2.70	3.06	2.46	3.08	3.45	3.89	3.07	ns
LVC MOS15_S6	0.59	0.62	0.73	0.86	2.24	2.51	2.88	2.33	2.88	3.26	3.71	2.94	ns
LVC MOS15_S8	0.59	0.62	0.73	0.86	1.91	2.16	2.49	2.05	2.55	2.91	3.31	2.66	ns
LVC MOS15_S12	0.59	0.62	0.73	0.86	1.77	1.98	2.23	1.97	2.41	2.73	3.05	2.58	ns
LVC MOS15_S16	0.59	0.62	0.73	0.86	1.62	1.81	2.02	1.85	2.26	2.56	2.84	2.46	ns
LVC MOS15_F2	0.59	0.62	0.73	0.86	3.38	3.69	4.18	2.74	4.02	4.44	5.00	3.35	ns
LVC MOS15_F4	0.59	0.62	0.73	0.86	2.04	2.21	2.44	1.72	2.68	2.97	3.26	2.33	ns
LVC MOS15_F6	0.59	0.62	0.73	0.86	1.47	1.74	2.09	1.49	2.10	2.50	2.91	2.10	ns
LVC MOS15_F8	0.59	0.62	0.73	0.86	1.31	1.46	1.61	1.47	1.95	2.22	2.43	2.08	ns
LVC MOS15_F12	0.59	0.62	0.73	0.86	1.21	1.34	1.45	1.44	1.84	2.10	2.27	2.05	ns
LVC MOS15_F16	0.59	0.62	0.73	0.86	1.18	1.31	1.41	1.41	1.82	2.07	2.23	2.02	ns
LVC MOS12_S2	0.64	0.67	0.78	0.95	3.38	3.80	4.48	3.27	4.02	4.55	5.30	3.88	ns
LVC MOS12_S4	0.64	0.67	0.78	0.95	2.62	2.94	3.43	2.76	3.26	3.70	4.25	3.37	ns
LVC MOS12_S6	0.64	0.67	0.78	0.95	2.05	2.33	2.72	2.24	2.69	3.08	3.54	2.85	ns
LVC MOS12_S8	0.64	0.67	0.78	0.95	1.94	2.18	2.51	2.16	2.58	2.94	3.33	2.77	ns
LVC MOS12_F2	0.64	0.67	0.78	0.95	2.84	3.15	3.62	2.47	3.48	3.90	4.44	3.08	ns
LVC MOS12_F4	0.64	0.67	0.78	0.95	1.97	2.18	2.44	1.69	2.61	2.93	3.26	2.30	ns
LVC MOS12_F6	0.64	0.67	0.78	0.95	1.33	1.51	1.70	1.43	1.96	2.26	2.52	2.04	ns

Table 21 specifies the values of T_{IOTPHZ} and $T_{IOIBUFDISABLE}$. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). $T_{IOIBUFDISABLE}$ is described as the IOB delay from IBUFDISABLE to O output. In HP I/O banks, the internal DCI termination turn-off time is always faster than T_{IOTPHZ} when the DCITERMDISABLE pin is used. In HR I/O banks, the internal IN_TERM termination turn-off time is always faster than T_{IOTPHZ} when the INTERMDISABLE pin is used.

Table 21: IOB 3-state Output Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{IOTPHZ}	T input to pad high-impedance	0.76	0.86	0.99	0.62	ns
$T_{IOIBUFDISABLE_HR}$	IBUF turn-on time from IBUFDISABLE to O output for HR I/O banks	1.72	1.89	2.14	2.17	ns
$T_{IOIBUFDISABLE_HP}$	IBUF turn-on time from IBUFDISABLE to O output for HP I/O banks	1.31	1.46	1.76	1.86	ns

Input/Output Logic Switching Characteristics

Table 22: ILOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T _{ICE1CK} /T _{ICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.42/0.00	0.48/0.00	0.67/0.00	0.56/−0.16	ns
T _{ISRCK} /T _{ICKSR}	SR pin Setup/Hold with respect to CLK	0.53/0.01	0.61/0.01	0.99/0.01	0.88/−0.30	ns
T _{IDOCKE2} /T _{IOCKDE2}	D pin Setup/Hold with respect to CLK without Delay (HP I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	0.01/0.41	ns
T _{IDOCKDE2} /T _{IOCKDDE2}	DDLY pin Setup/Hold with respect to CLK (using IDELAY) (HP I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	0.01/0.41	ns
T _{IDOCKE3} /T _{IOCKDE3}	D pin Setup/Hold with respect to CLK without Delay (HR I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	0.01/0.41	ns
T _{IDOCKDE3} /T _{IOCKDDE3}	DDLY pin Setup/Hold with respect to CLK (using IDELAY) (HR I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	0.01/0.41	ns
Combinatorial						
T _{IDIE2}	D pin to O pin propagation delay, no Delay (HP I/O banks only)	0.09	0.10	0.12	0.14	ns
T _{IDIDE2}	DDLY pin to O pin propagation delay (using IDELAY) (HP I/O banks only)	0.10	0.11	0.13	0.15	ns
T _{IDIE3}	D pin to O pin propagation delay, no Delay (HR I/O banks only)	0.09	0.10	0.12	0.14	ns
T _{IDIDE3}	DDLY pin to O pin propagation delay (using IDELAY) (HR I/O banks only)	0.10	0.11	0.13	0.15	ns
Sequential Delays						
T _{IDLOE2}	D pin to Q1 pin using flip-flop as a latch without Delay (HP I/O banks only)	0.36	0.39	0.45	0.54	ns
T _{IDLODE2}	DDLY pin to Q1 pin using flip-flop as a latch (using IDELAY) (HP I/O banks only)	0.36	0.39	0.45	0.55	ns
T _{IDLOE3}	D pin to Q1 pin using flip-flop as a latch without Delay (HR I/O banks only)	0.36	0.39	0.45	0.54	ns
T _{IDLODE3}	DDLY pin to Q1 pin using flip-flop as a latch (using IDELAY) (HR I/O banks only)	0.36	0.39	0.45	0.55	ns
T _{ICKQ}	CLK to Q outputs	0.47	0.50	0.58	0.71	ns
T _{RQ_ILOGICE2}	SR pin to OQ/TQ out (HP I/O banks only)	0.84	0.94	1.16	1.32	ns
T _{GSRQ_ILOGICE2}	Global Set/Reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	11.39	ns
T _{RQ_ILOGICE3}	SR pin to OQ/TQ out (HR I/O banks only)	0.84	0.94	1.16	1.32	ns
T _{GSRQ_ILOGICE3}	Global Set/Reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	11.39	ns
Set/Reset						
T _{RPW_ILOGICE2}	Minimum Pulse Width, SR inputs (HP I/O banks only)	0.54	0.63	0.63	0.68	ns, Min
T _{RPW_ILOGICE3}	Minimum Pulse Width, SR inputs (HR I/O banks only)	0.54	0.63	0.63	0.68	ns, Min

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 29: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T _{SHCKO}	Clock to A – B outputs	0.68	0.70	0.85	1.08	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	0.91	0.95	1.15	1.44	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS_LRAM} /T _{DH_LRAM}	A – D inputs to CLK	0.45/0.23	0.45/0.24	0.54/0.27	0.69/0.33	ns, Min
T _{AS_LRAM} /T _{AH_LRAM}	Address An inputs to clock	0.13/0.50	0.14/0.50	0.17/0.58	0.21/0.63	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.40/0.16	0.42/0.17	0.52/0.23	0.63/0.23	ns, Min
T _{WS_LRAM} /T _{WH_LRAM}	WE input to clock	0.29/0.09	0.30/0.09	0.36/0.09	0.46/0.10	ns, Min
T _{CECK_LRAM} / T _{CKCE_LRAM}	CE input to CLK	0.29/0.09	0.30/0.09	0.37/0.09	0.47/0.10	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.68	0.77	0.91	1.11	ns, Min
T _{MCP}	Minimum clock period	1.35	1.54	1.82	2.22	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 30: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	0.96	0.98	1.20	1.35	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.19	1.23	1.50	1.72	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	0.89	0.91	1.10	1.25	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS_SHFREG} / T _{WH_SHFREG}	WE input	0.26/0.09	0.27/0.09	0.33/0.09	0.41/0.10	ns, Min
T _{CECK_SHFREG} / T _{CKCE_SHFREG}	CE input to CLK	0.27/0.09	0.28/0.09	0.33/0.09	0.42/0.10	ns, Min
T _{DS_SHFREG} / T _{DH_SHFREG}	A – D inputs to CLK	0.28/0.26	0.28/0.26	0.33/0.30	0.41/0.36	ns, Min
Clock CLK						
T _{MPW_SHFREG}	Minimum pulse width	0.55	0.65	0.78	0.91	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time.

Block RAM and FIFO Switching Characteristics

Table 31: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Block RAM and FIFO Clock-to-Out Delays						
T_{RCKO_DO} and $T_{RCKO_DO_REG}^{(1)}$	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.57	1.80	2.08	2.44	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.54	0.63	0.75	0.86	ns, Max
$T_{RCKO_DO_ECC}$ and $T_{RCKO_DO_ECC_REG}$	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.35	2.58	3.26	4.49	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.62	0.69	0.80	0.94	ns, Max
$T_{RCKO_DO_CASCOU}$ and $T_{RCKO_DO_CASCOU_REG}$	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.21	2.45	2.80	3.19	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	0.98	1.08	1.24	1.32	ns, Max
T_{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.65	0.74	0.89	0.97	ns, Max
$T_{RCKO_POINTERS}$	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.79	0.87	0.98	1.10	ns, Max
$T_{RCKO_PARITY_ECC}$	Clock CLK to ECCPARITY in ECC encode only mode	0.66	0.72	0.80	0.93	ns, Max
$T_{RCKO_SDBIT_ECC}$ and $T_{RCKO_SDBIT_ECC_REG}$	Clock CLK to BITERR (without output register)	2.17	2.38	3.01	4.15	ns, Max
	Clock CLK to BITERR (with output register)	0.57	0.65	0.76	0.89	ns, Max
$T_{RCKO_RDADDR_ECC}$ and $T_{RCKO_RDADDR_ECC_REG}$	Clock CLK to RDADDR output with ECC (without output register)	0.64	0.74	0.90	0.98	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.71	0.79	0.92	1.10	ns, Max
Setup and Hold Times Before/After Clock CLK						
$T_{RCK_ADDR}/T_{RCKC_ADDR}$	ADDR inputs ⁽⁸⁾	0.38/0.27	0.42/0.28	0.48/0.31	0.65/0.38	ns, Min
$T_{RDCK_DI_WF_NC}/T_{RCKD_DI_WF_NC}$	Data input setup/hold time when block RAM is configured in WRITE_FIRST or NO_CHANGE mode ⁽⁹⁾	0.49/0.51	0.55/0.53	0.63/0.57	0.78/0.64	ns, Min
$T_{RDCK_DI_RF}/T_{RCKD_DI_RF}$	Data input setup/hold time when block RAM is configured in READ_FIRST mode ⁽⁹⁾	0.17/0.25	0.19/0.29	0.21/0.35	0.25/0.32	ns, Min
$T_{RDCK_DI_ECC}/T_{RCKD_DI_ECC}$	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.42/0.37	0.47/0.39	0.53/0.43	0.66/0.46	ns, Min
$T_{RDCK_DI_ECCW}/T_{RCKD_DI_ECCW}$	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.79/0.37	0.87/0.39	0.99/0.43	1.17/0.41	ns, Min
$T_{RDCK_DI_ECC_FIFO}/T_{RCKD_DI_ECC_FIFO}$	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.89/0.47	0.98/0.50	1.12/0.54	1.32/0.65	ns, Min
$T_{RCK_INJECTBITERR}/T_{RCKC_INJECTBITERR}$	Inject single/double bit error in ECC mode	0.49/0.30	0.55/0.31	0.63/0.34	0.78/0.41	ns, Min
T_{RCK_EN}/T_{RCKC_EN}	Block RAM Enable (EN) input	0.30/0.17	0.33/0.18	0.38/0.20	0.48/0.22	ns, Min
$T_{RCK_REGCE}/T_{RCKC_REGCE}$	CE input of output register	0.21/0.13	0.25/0.13	0.31/0.14	0.34/0.16	ns, Min
$T_{RCK_RSTREG}/T_{RCKC_RSTREG}$	Synchronous RSTREG input	0.25/0.06	0.27/0.06	0.29/0.06	0.35/0.06	ns, Min

DSP48E1 Switching Characteristics

Table 32: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock						
T _{DSPDCK_A_AREG} /T _{DSPCKD_A_AREG}	A input to A register CLK	0.24/ 0.12	0.27/ 0.14	0.31/ 0.16	0.38/ 0.12	ns
T _{DSPDCK_B_BREG} /T _{DSPCKD_B_BREG}	B input to B register CLK	0.28/ 0.13	0.32/ 0.14	0.39/ 0.15	0.51/ 0.16	ns
T _{DSPDCK_C_CREG} /T _{DSPCKD_C_CREG}	C input to C register CLK	0.15/ 0.15	0.17/ 0.17	0.20/ 0.20	0.31/ 0.21	ns
T _{DSPDCK_D_DREG} /T _{DSPCKD_D_DREG}	D input to D register CLK	0.21/ 0.19	0.27/ 0.22	0.35/ 0.26	0.46/ 0.20	ns
T _{DSPDCK_ACIN_AREG} /T _{DSPCKD_ACIN_AREG}	ACIN input to A register CLK	0.21/ 0.12	0.24/ 0.14	0.27/ 0.16	0.31/ 0.12	ns
T _{DSPDCK_BCIN_BREG} /T _{DSPCKD_BCIN_BREG}	BCIN input to B register CLK	0.22/ 0.13	0.25/ 0.14	0.30/ 0.15	0.34/ 0.16	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock						
T _{DSPDCK_{A,B}_MREG_MULT} / T _{DSPCKD_B_MREG_MULT}	{A, B,} input to M register CLK using multiplier	2.04/ −0.01	2.34/ −0.01	2.79/ −0.01	3.66/ −0.06	ns
T _{DSPDCK_{A,B}_ADREG} / T _{DSPCKD_D_ADREG}	{A, D} input to AD register CLK	1.09/ −0.02	1.25/ −0.02	1.49/ −0.02	1.94/ −0.23	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock						
T _{DSPDCK_{A,B}_PREG_MULT} / T _{DSPCKD_{A,B}_PREG_MULT}	{A, B,} input to P register CLK using multiplier	3.41/ −0.24	3.90/ −0.24	4.64/ −0.24	5.89/ −0.41	ns
T _{DSPDCK_D_PREG_MULT} / T _{DSPCKD_D_PREG_MULT}	D input to P register CLK using multiplier	3.33/ −0.62	3.81/ −0.62	4.53/ −0.62	5.70/ −1.42	ns
T _{DSPDCK_{A,B}_PREG} / T _{DSPCKD_{A,B}_PREG}	A or B input to P register CLK not using multiplier	1.47/ −0.24	1.68/ −0.24	2.00/ −0.24	2.37/ −0.41	ns
T _{DSPDCK_C_PREG} / T _{DSPCKD_C_PREG}	C input to P register CLK not using multiplier	1.30/ −0.22	1.49/ −0.22	1.78/ −0.22	2.11/ −0.36	ns
T _{DSPDCK_PCIN_PREG} / T _{DSPCKD_PCIN_PREG}	PCIN input to P register CLK	1.12/ −0.13	1.28/ −0.13	1.52/ −0.13	1.81/ −0.21	ns
Setup and Hold Times of the CE Pins						
T _{DSPDCK_{CEA;CEB}_{AREG;BREG}} / T _{DSPCKD_{CEA;CEB}_{AREG;BREG}}	{CEA; CEB} input to {A; B} register CLK	0.30/ 0.05	0.36/ 0.06	0.44/ 0.09	0.55/ 0.09	ns
T _{DSPDCK_CEC_CREG} / T _{DSPCKD_CEC_CREG}	CEC input to C register CLK	0.24/ 0.08	0.29/ 0.09	0.36/ 0.11	0.43/ 0.11	ns
T _{DSPDCK_CED_DREG} / T _{DSPCKD_CED_DREG}	CED input to D register CLK	0.31/ −0.02	0.36/ −0.02	0.44/ −0.02	0.58/ 0.12	ns
T _{DSPDCK_CEM_MREG} / T _{DSPCKD_CEM_MREG}	CEM input to M register CLK	0.26/ 0.15	0.29/ 0.17	0.33/ 0.20	0.39/ 0.25	ns
T _{DSPDCK_CEP_PREG} / T _{DSPCKD_CEP_PREG}	CEP input to P register CLK	0.31/ 0.01	0.36/ 0.01	0.45/ 0.01	0.54/ 0.00	ns

MMCM Switching Characteristics

Table 38: MMCM Specification

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
MMCM_F _{INMAX}	Maximum Input Clock Frequency	1066.00	933.00	800.00	800.00	MHz
MMCM_F _{INMIN}	Minimum Input Clock Frequency	10.00	10.00	10.00	10.00	MHz
MMCM_F _{INJITTER}	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max				
MMCM_F _{INDUTY}	Allowable Input Duty Cycle: 10—49 MHz	25.00	25.00	25.00	25.00	%
	Allowable Input Duty Cycle: 50—199 MHz	30.00	30.00	30.00	30.00	%
	Allowable Input Duty Cycle: 200—399 MHz	35.00	35.00	35.00	35.00	%
	Allowable Input Duty Cycle: 400—499 MHz	40.00	40.00	40.00	40.00	%
	Allowable Input Duty Cycle: >500 MHz	45.00	45.00	45.00	45.00	%
MMCM_F _{MIN_PSCLK}	Minimum Dynamic Phase Shift Clock Frequency	0.01	0.01	0.01	0.01	MHz
MMCM_F _{MAX_PSCLK}	Maximum Dynamic Phase Shift Clock Frequency	550.00	500.00	450.00	450.00	MHz
MMCM_F _{VCOMIN}	Minimum MMCM VCO Frequency	600.00	600.00	600.00	600.00	MHz
MMCM_F _{VCOMAX}	Maximum MMCM VCO Frequency	1600.00	1440.00	1200.00	1200.00	MHz
MMCM_F _{BANDWIDTH}	Low MMCM Bandwidth at Typical ⁽¹⁾	1.00	1.00	1.00	1.00	MHz
	High MMCM Bandwidth at Typical ⁽¹⁾	4.00	4.00	4.00	4.00	MHz
MMCM_T _{STATPHAOFFSET}	Static Phase Offset of the MMCM Outputs ⁽²⁾	0.12	0.12	0.12	0.12	ns
MMCM_T _{OUTJITTER}	MMCM Output Jitter	Note 3				
MMCM_T _{OUTDUTY}	MMCM Output Clock Duty Cycle Precision ⁽⁴⁾	0.20	0.20	0.20	0.25	ns
MMCM_T _{LOCKMAX}	MMCM Maximum Lock Time	100.00	100.00	100.00	100.00	μs
MMCM_F _{OUTMAX}	MMCM Maximum Output Frequency	1066.00	933.00	800.00	800.00	MHz
MMCM_F _{OUTMIN}	MMCM Minimum Output Frequency ⁽⁵⁾⁽⁶⁾	4.69	4.69	4.69	4.69	MHz
MMCM_T _{EXTFDVAR}	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max				
MMCM_RST _{MINPULSE}	Minimum Reset Pulse Width	5.00	5.00	5.00	5.00	ns
MMCM_F _{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	550.00	500.00	450.00	450.00	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300.00	300.00	300.00	300.00	MHz
MMCM_F _{PFDMIN}	Minimum Frequency at the Phase Frequency Detector	10.00	10.00	10.00	10.00	MHz
MMCM_T _{FBDELAY}	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
MMCM Switching Characteristics Setup and Hold						
T _{MMCMDCK_PSEN} / T _{MMCMCKD_PSEN}	Setup and Hold of Phase Shift Enable	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T _{MMCMDCK_PSINCDEC} / T _{MMCMCKD_PSINCDEC}	Setup and Hold of Phase Shift Increment/Decrement	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T _{MMCMCKO_PSDONE}	Phase Shift Clock-to-Out of PSDONE	0.59	0.68	0.81	0.78	ns
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
T _{MMCMDCK_DADDR} / T _{MMCMCKD_DADDR}	DADDR Setup/Hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{MMCMDCK_DI} / T _{MMCMCKD_DI}	DI Setup/Hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min

Table 39: PLL Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
PLL_F _{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	550.00	500.00	450.00	450.00	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300.00	300.00	300.00	300.00	MHz
PLL_F _{PFDMIN}	Minimum Frequency at the Phase Frequency Detector	19.00	19.00	19.00	19.00	MHz
PLL_T _{FBDELAY}	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
Dynamic Reconfiguration Port (DRP) for PLL Before and After DCLK						
T _{PLLCKC_DADDR} / T _{PLLCKC_DADDR}	Setup and hold of D address	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLCKC_DI} / T _{PLLCKC_DI}	Setup and hold of D input	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLCKC_DEN} / T _{PLLCKC_DEN}	Setup and hold of D enable	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T _{PLLCKC_DWE} / T _{PLLCKC_DWE}	Setup and hold of D write enable	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F _{DCK}	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The PLL does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any PLL outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as $F_{VCO}/128$ assuming output duty cycle is 50%.

Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

Table 40: Clock-Capable Clock Input to Output Delay Without MMCM/PLL (Near Clock Region)

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>without</i> MMCM/PLL.							
T _{ICKOF}	Clock-capable clock input and OUTFF <i>without</i> MMCM/PLL (near clock region)	XC7K70T	4.98	5.49	6.17	7.04	ns
		XC7K160T	5.23	5.77	6.48	7.38	ns
		XC7K325T	5.72	6.31	7.09	8.07	ns
		XC7K355T	5.34	5.87	6.57	7.51	ns
		XC7K410T	5.84	6.44	7.22	8.21	ns
		XC7K420T	5.50	6.04	6.77	7.73	ns
		XC7K480T	5.50	6.04	6.77	7.73	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Table 41: Clock-Capable Clock Input to Output Delay Without MMCM/PLL (Far Clock Region)

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>without</i> MMCM/PLL.							
T _{ICKOFFAR}	Clock-capable clock input and OUTFF <i>without</i> MMCM/PLL (far clock region)	XC7K70T	5.29	5.83	6.55	7.47	ns
		XC7K160T	5.84	6.45	7.24	8.24	ns
		XC7K325T	6.33	6.99	7.84	8.92	ns
		XC7K355T	5.95	6.55	7.32	8.36	ns
		XC7K410T	6.45	7.12	7.97	9.07	ns
		XC7K420T	6.41	7.06	7.90	9.01	ns
		XC7K480T	6.41	7.06	7.90	9.01	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

Table 45: Global Clock Input Setup and Hold Without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾							
T _{PSFD} / T _{PHFD}	Full Delay (Legacy Delay or Default Delay) Global Clock Input and IFF ⁽²⁾ without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks	XC7K70T	2.83/−0.29	2.95/−0.29	3.15/−0.29	4.96/−0.33	ns
		XC7K160T	3.17/−0.35	3.29/−0.35	3.55/−0.35	5.54/−0.49	ns
		XC7K325T	2.83/−0.06	2.94/−0.06	3.15/−0.06	5.18/−0.14	ns
		XC7K355T	3.26/−0.32	3.41/−0.32	3.67/−0.32	5.84/−0.49	ns
		XC7K410T	3.43/−0.34	3.59/−0.34	3.88/−0.34	6.21/−0.54	ns
		XC7K420T	3.37/−0.27	3.48/−0.27	3.76/−0.27	6.00/−0.52	ns
		XC7K480T	3.37/−0.27	3.48/−0.27	3.76/−0.27	6.00/−0.52	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch
- A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

Table 46: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾							
T _{PSMMCMCC} / T _{PHMMCMCC}	No Delay clock-capable clock input and IFF ⁽²⁾ with MMCM	XC7K70T	2.39/−0.22	2.65/−0.22	2.94/−0.22	2.21/−0.44	ns
		XC7K160T	2.49/−0.20	2.77/−0.20	3.07/−0.20	2.38/−0.47	ns
		XC7K325T	2.55/−0.16	2.85/−0.16	3.14/−0.16	2.60/−0.47	ns
		XC7K355T	2.43/−0.16	2.73/−0.16	3.00/−0.16	2.47/−0.43	ns
		XC7K410T	2.55/−0.16	2.84/−0.16	3.14/−0.16	2.58/−0.47	ns
		XC7K420T	2.47/−0.09	2.73/−0.09	3.02/−0.09	2.40/−0.41	ns
		XC7K480T	2.47/−0.09	2.73/−0.09	3.02/−0.09	2.40/−0.41	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch
- Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 53: GTX Transceiver Performance (Cont'd)

Symbol	Description	Output Divider	Speed Grade								Units
			1.0V						0.9V		
			-3		-2/-2L		-1 ⁽¹⁾		-2L ⁽²⁾		
			Package Type								
			FF	FB	FF	FB	FF	FB	FF	FB	
F _{GQPLL} RANGE2	GTX transceiver QPLL frequency range 2		9.8–12.5		9.8–10.3125		N/A		N/A		GHz

Notes:

1. The -1 speed grade requires a 4-byte internal data width for operation above 5.0 Gb/s.
2. The -2L (0.9V) speed grade requires a 4-byte internal data width for operation above 3.8 Gb/s.
3. Data rates between 8.0 Gb/s and 9.8 Gb/s are not available.
4. For QPLL line rate range 2, the maximum line rate with the divider N set to 66 is 10.3125Gb/s.

Table 54: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
F _{GTXDRPCLK}	GTXDRPCLK maximum frequency	175.01	175.01	156.25	125.00	MHz

Table 55: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F _{GCLK}	Reference clock frequency range	-3 speed grade	60	–	700	MHz
		All other speed grades	60	–	670	MHz
T _{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T _{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T _{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	50	60	%

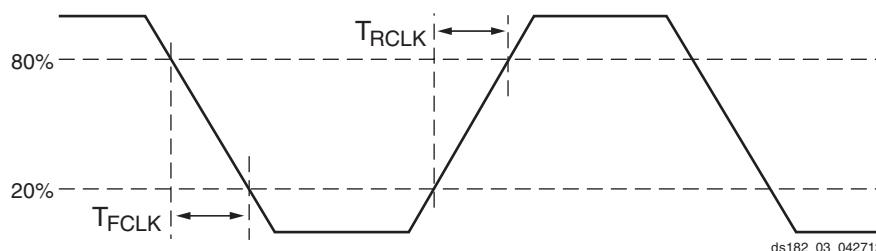


Figure 3: Reference Clock Timing Parameters

GTX Transceiver Protocol Jitter Characteristics

For Table 60 through Table 65, the [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) contains recommended settings for optimal usage of protocol specific characteristics.

Table 60: Gigabit Ethernet Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
Gigabit Ethernet Transmitter Jitter Generation				
Total transmitter jitter (T _{TJ})	1250	–	0.24	UI
Gigabit Ethernet Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	1250	0.749	–	UI

Table 61: XAUI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
XAUI Transmitter Jitter Generation				
Total transmitter jitter (T _{TJ})	3125	–	0.35	UI
XAUI Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	3125	0.65	–	UI

Table 62: PCI Express Protocol Characteristics⁽¹⁾

Standard	Description		Line Rate (Mb/s)	Min	Max	Units
PCI Express Transmitter Jitter Generation						
PCI Express Gen 1	Total transmitter jitter		2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter		5000	–	0.25	UI
PCI Express Gen 3 ⁽²⁾	Total transmitter jitter uncorrelated		8000	–	31.25	ps
	Deterministic transmitter jitter uncorrelated			–	12	ps
PCI Express Receiver High Frequency Jitter Tolerance						
PCI Express Gen 1	Total receiver jitter tolerance		2500	0.65	–	UI
PCI Express Gen 2 ⁽³⁾	Receiver inherent timing error		5000	0.40	–	UI
	Receiver inherent deterministic timing error			0.30	–	UI
PCI Express Gen 3 ⁽²⁾	Receiver sinusoidal jitter tolerance	0.03 MHz–1.0 MHz	8000	1.00	–	UI
		1.0 MHz–10 MHz		Note 4	–	UI
		10 MHz–100 MHz		0.10	–	UI

Notes:

1. Tested per card electromechanical (CEM) methodology.
2. PCI-SIG 3.0 certification and compliance test boards are currently not available.
3. Using common REFCLK.
4. Between 1 MHz and 10 MHz the minimum sinusoidal jitter roll-off with a slope of 20dB/decade.

Table 65: CPRI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
CPRI Transmitter Jitter Generation				
Total transmitter jitter	614.4	–	0.35	UI
	1228.8	–	0.35	UI
	2457.6	–	0.35	UI
	3072.0	–	0.35	UI
	4915.2	–	0.3	UI
	6144.0	–	0.3	UI
	9830.4	–	Note 1	UI
CPRI Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	614.4	0.65	–	UI
	1228.8	0.65	–	UI
	2457.6	0.65	–	UI
	3072.0	0.65	–	UI
	4915.2	0.95	–	UI
	6144.0	0.95	–	UI
	9830.4	Note 1	–	UI

Notes:

1. Tested per SFP+ specification, see Table 64.

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 66: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
F _{PIPECLK}	Pipe clock maximum frequency	250.00	250.00	250.00	250.00	MHz
F _{USERCLK}	User clock maximum frequency	500.00	500.00	250.00	250.00	MHz
F _{USERCLK2}	User clock 2 maximum frequency	250.00	250.00	250.00	250.00	MHz
F _{DRPCLK}	DRP clock maximum frequency	250.00	250.00	250.00	250.00	MHz

Table 67: XADC Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
XADC Reference⁽⁵⁾						
External Reference	V _{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
On-Chip Reference		Ground V _{REFP} pin to AGND, T _j = -40°C to 100°C	1.2375	1.25	1.2625	V

Notes:

- Offset and gain errors are removed by enabling the XADC automatic gain calibration feature. The values are specified for when this feature is enabled.
- Only specified for new BitGen option XADCEnhancedLinearity = ON.
- See the ADC chapter in [UG480: 7 Series FPGAs XADC User Guide](#) for a detailed description.
- See the Timing chapter in [UG480: 7 Series FPGAs XADC User Guide](#) for a detailed description.
- Any variation in the reference voltage from the nominal V_{REFP} = 1.25V and V_{REFN} = 0V will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by ±4% is permitted. On-chip reference variation is ±1%.

Configuration Switching Characteristics

Table 68: Configuration Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program latency	5	5	5	5	ms, Max
T _{POR} ⁽¹⁾	Power-on reset (50 ms ramp rate time)	10/50	10/50	10/50	10/50	ms, Min/Max
	Power-on reset (1 ms ramp rate time)	10/35	10/35	10/35	10/35	ms, Min/Max
T _{PROGRAM}	Program pulse width	250	250	250	250	ns, Min
CCLK Output (Master Mode)						
T _{ICCK}	Master CCLK output delay	150	150	150	150	ns, Min
T _{MCCKL}	Master CCLK clock Low time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
F _{MCCK}	Master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
	Master CCLK frequency for AES encrypted x16	50.00	50.00	50.00	35.00	MHz, Max
F _{MCCK_START}	Master CCLK frequency at start of configuration	3.00	3.00	3.00	3.00	MHz, Typ
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK	±50	±50	±50	±50	%, Max
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time	2.50	2.50	2.50	2.50	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time	2.50	2.50	2.50	2.50	ns, Min
F _{SCCK}	Slave CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
EMCCLK Input (Master Mode)						
T _{EMCCKL}	External master CCLK Low time	2.50	2.50	2.50	2.50	ns, Min
T _{EMCCKH}	External master CCLK High time	2.50	2.50	2.50	2.50	ns, Min
F _{EMCCK}	External master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
Internal Configuration Access Port						
F _{ICAPCK}	Internal configuration access port (ICAPE2)	100.00	100.00	100.00	70.00	MHz, Max

Revision History

The following table shows the revision history for this document:

Date	Version	Description
03/01/11	1.0	Initial Xilinx release.
04/01/11	1.1	Added the XC7K355T, XC7K420T, and XC7K480T devices throughout data sheet. Added the extended temperature range discussion to page 1 . Updated V_{CCAUX_IO} in Table 2 . Edits to clarify Power-On/Off Power Supply Sequencing power sequencing discussion. Added I_{CCAUX_IO} and I_{CCBRAM} to Table 6 and Table 7 . Updated $MMCM_F_{INDUTY}$ and added $F_{INJITTER}$, $T_{OUTJITTER}$, $T_{EXTFVAR}$, and Note 3 to Table 38 . Removed the SBG324 package from Table 50 . Updated the Notice of Disclaimer .
10/04/11	1.2	Replaced -1L with -2L throughout this data sheet. Updated Min/Max values and removed Note 5 from Table 2 . Clarified Power-On/Off Power Supply Sequencing power sequencing discussion including adding $T_{VCCO2VCCAUX}$ to Table 8 . Updated V_{ICM} in Table 12 and Table 13 . Added Note 1 to Table 12 . Updated Table 69 including adding Note 1 . Added <i>Absolute Maximum Ratings for GTX Transceivers</i> . Revised the reference clock maximum frequency (F_{GCLK}) in Table 55 . Added Table 57 . Added LVTTTL and removed SSTL135_II and SSTL15_II specifications from Table 19 . Removed HSTL_III from Table 20 . Removed the <i>I/O Standard Adjustment Measurement Methodology</i> section. Use IBIS for more accurate information and measurements. Updated $T_{DELAYPAT_JIT}$ in Table 26 . Added T_{AS}/T_{AH} to Table 28 . Added $T_{RDCK_DI_WF_NC}/T_{RCKD_DI_WF_NC}$ and $T_{RDCK_DI_RF}/T_{RCKD_DI_RF}$ to Table 31 . Completely updated Table 68 . Updated the AC Switching Characteristics in Table 19 , Table 20 , Table 21 , Table 22 , Table 23 , Table 24 , Table 26 through Table 38 , Table 40 through Table 37 , and Table 67 .
11/03/11	1.3	Revised the V_{OCM} specification in Table 12 . Updated the AC Switching Characteristics based upon the ISE 13.3 v1.02 speed specification throughout document including Table 19 and Table 20 . Added $MMCM_T_{FBDELAY}$ while adding $MMCM_$ to the symbol names of a few specifications in Table 38 and PLL to the symbol names in Table 39 . In Table 40 through Table 47 , updated the pin-to-pin descriptions with the SSTL15 standard. Updated units in Table 49 .
02/13/12	1.4	Updated summary description on page 1 . In Table 2 , revised V_{CCO} for the 3.3V HR I/O banks and updated T_j . Added typical values to Table 3 . Updated the notes in Table 6 . Added MGTAVCC, MGTAVTT, and MGTVCCAUX power supply ramp times to Table 8 . Rearranged Table 9 , added Mobile_DDR, HSTL_I_18, HSTL_II_18, HSUL_12, SSTL135_R, SSTL15_R, and SSTL12 and removed DIFF_SSTL135, DIFF_SSTL18_I, DIFF_SSTL18_II, DIFF_HSTL_I, and DIFF_HSTL_II. Added Table 10 and Table 11 . Revised the specifications in Table 12 and Table 13 . Updated the eFUSE Programming Conditions section and removed the endurance table. Added the IO_FIFO Switching Characteristics table. Revised I_{CCADC} and updated Note 1 in Table 67 . Revised DDR LVDS transmitter data width in Table 16 . Updated the AC Switching Characteristics based upon the ISE 13.4 v1.03 speed specification throughout document. Removed notes from Table 28 as they are no longer applicable. Updated specifications in Table 68 . Updated Note 1 in Table 37 . In the GTX Transceiver DC Input and Output Levels section: Revised V_{IN} , and added I_{DCIN} and I_{DCOUT} to Table 51 . Added Note 4 to Table 53 . In Table 55 , revised F_{GCLK} , removed T_{PHASE} , and added T_{DLOCK} . Revised specifications and added Note 2 to Table 57 . Added Table 58 and Table 59 along with GTX Transceiver Protocol Jitter Characteristics in Table 60 through Table 65 .
05/23/12	1.5	Reorganized entire data sheet including adding Table 44 and Table 48 . Updated T_{SOL} in Table 1 . Updated I_{BATT} and added R_{IN_TERM} to Table 3 . Added values to Table 6 and Table 7 . Updated Power-On/Off Power Supply Sequencing , page 6 with regards to GTX transceivers. Updated many parameters in Table 9 including SSTL135 and SSTL135_R. Removed V_{OX} column and added DIFF_HSUL_12 to Table 11 . Updated V_{OL} in Table 12 . Updated Table 16 and removed notes 2 and 3. Updated Table 17 . Updated the AC Switching Characteristics based upon the ISE 14.1 v1.04 for the -3, -2, -2L (1.0V), -1, and -2L (0.9V) speed specifications throughout the document. In Table 31 , updated Reset Delays section including Note 10 and Note 11 . Added data for T_{LOCK} and T_{DLOCK} in Table 55 . Updated many of the XADC specifications in Table 67 and added Note 2 . Updated and moved <i>Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK</i> section from Table 68 to Table 38 and Table 39 .